IN THE CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1.(Currently Amended) Polycrystalline alumina components optionally containing MgO in a concentration of at most 0.3 wt-%-characterized in that , wherein the alumina contains a concentration from 0.1 to 0.5 wt-% inclusive ZrO₂ inclusive as an additive and has an average crystal size≤2 μm, and a relative density higher than 99.95%, and is transparent with a real in-line transmission RIT≥30% measured over an angular aperture of at most 0.5° at a sample thickness of 0.8 mm and with a monochromatic wavelength of light λ.

2.(Currently Amended) Polyerystalline The polycrystalline alumina components according to claim 1, characterized in that wherein the average crystal size is ≤1 µm and the real in-line transmission RIT is at least 40%.

3.(Currently Amended) Polycrystalline-The polycrystalline alumina components according to claim 1, characterized in that wherein the ZrO₂ additive is in a concentration from 0.1 wt-% to 0.3 wt-%, inclusive.

- 4. (Currently Amended) Discharge A discharge lamp characterized in that the lamp is provided with comprising a discharge tube having a wall of a ceramic as claimed in claim 1.
- 5.(Currently Amended) <u>Lamp The discharge lamp</u> according to claim 4 characterized in that wherein the discharge tube has an ionisable filling containing a metal halide.
- 6.(Currently Amended) Method for forming a polycrystalline alumina component as claimed in claim 1 characterized in that the process wherein the method includes the steps acts of preparing a slurry of corundum power with a mean grain size ≤ 0.2 μm, adding a dopant, selected from zirconia and a zirconium containing precursor, casting the slurry in a mould to form a moulded body, drying and sintering of the moulded body thus formed, and

performing a HIP treatment at a temperature of at least 1150° C. for at least 2 hours.

- 7.(Currently Amended) Method The method according to claim 6, wherein the dopant is added as finely grained ZrO₂.
- 8.(Currently Amended) Method The method according to claim 6, wherein the finely grained ZrO₂-dopant has an average particle size of at most 100 nm.
 - 9.(Currently Amended) Method The method according to claim 6, wherein after the addition

of the zirconia dopant adding act, the prepared slurry is slip cast in a mould.

10.(Currently Amended) Method The method according to claim 6, wherein after the addition of the zirconia dopant the prepared slurry is gel cast in a mould.

11.(Currently Amended) Polycrystalline alumina components characterized in that the comprising alumina which contains a concentration between 0.1 to 0.5wt-% inclusive as an additive, has an average crystal size $\leq 2 \mu m$, and has a relative density higher than 0.3 wt-%, and is transparent.

12.(Currently Amended) The Polycrystalline alumina components of claim 11-further characterized in that, wherein the alumina contains MgO in a concentration of at most 0.3 wt-%.

13.(Currently Amended) Discharge A discharge lamp characterized in that the is provided with comprising a discharge tube having a wall of a ceramic as claimed in claim 11.

14.(Currently Amended) Method A method for forming a polycrystalline alumina component as claimed in claim 11-characterized in that, wherein the process method includes the steps acts of:

preparing a slurry of corundum power with a mean grain size $\leq 0.2~\mu m$, adding a dopant, selected from zirconia and a zirconium containing precursor,

casting the slurry in a mould to form a moulded body, drying and sintering of the moulded

body-thus-formed, and

performing a HIP treatment at a temperature of at least 1150° C. for at least 2 hours.

15.(New) The Polycrystalline alumina components of claim 11, wherein the transparency of the alumina is at least 30% having a real in-line transmission RIT \geq 30% measured over an angular aperture of at most 0.5° at a sample thickness of 0.8 mm and with a monochromatic wavelength of light λ .

16.(New) The polycrystalline alumina components of claim 11, wherein the RIT is based on a following relationship:

$$RIT = (1 - R) \exp(-\frac{3\pi^2 G d\Delta n^2}{2\lambda_0^2})$$

where

R is a coefficient of surface reflection,

d is the sample thickness,

G is the average crystal size,

Δn is an effective birefringence of alpha-alumina calculated as a weighted average of refractive index differences between each of main optical axes, and

 λ_0 is the monochromatic wavelength of the light in vacuum.